

4/17/2012

## RELIABILITY MONITOR REPORT FOR

## MFN 1.2µm Silicon Gate CMOS (S12)

## **MAXIM Integrated Products**

120 San Gabriel Dr. Sunnyvale, CA 94086

This Report was prepared by Maxim Reliability Engineering

## Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

The calculated failure	e rate f	or devices usina this	process is:					
FAILURE	RATE:	MTTF (YRS): 1	5309 QU	ANTIT	Y: 79	F/	AILS:	0 FITS: 7
The parameters used	d to ca	Iculate this failure rat	te are as follow	/S:				
, Cf: 60%		Ea: 0.7	Tu: 2	5 °C	;			
The reliability data fo data section includes and 3/31/2012 .	llows a the la	and in this section is test data available.	the detailed rel This report cov	iability ⁄ers da	data b ta betv	oy stress. T ween 4/1/2	he rel 011	ability
Process Information	n:							
Process Descriptio	n:	MFN 1.2µm Silic	on Gate CMOS	S (S12	)			
OPERATING LIFE								
DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READ	POINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1141	MAX6138BEXR25/V+T	135C	1000	HRS	79	0	N4V2CA096F
					10		U	
	DATE	TEOT	CONDITION		DOINT	OUANTITY		
DESCRIPTION	CODE	VEHICLE	CONDITION	READ	POINT	QUANTITY	FAILS	NO.
STORAGE LIFE	1141	MAX6138BEXR25/V+T	150C	1024	HRS	50	0	N4V2CA096F
					To	tal:	0	
TEMPERATURE CYCI	LE							
DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READ	POINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1030	MAX6008AEUR+	-65C TO 150C	1000	CYS	67	0	N93CCA178B#
TEMP CYCLE, 5' RAMP, 10' DWELL	1030	MAX6008AEUR+	-65C TO 150C	1000	CYS	65	0	N93CCA178CX
TEMP CYCLE, 5' RAMP, 10' DWELL	1030	MAX6008AEUR+	-65C TO 150C	1000	CYS	67	0	N93CCA178GX
TEMP CYCLE, 5' RAMP, 10' DWELL	1141	MAX6138BEXR25/V+T	-65C TO 150C	1000	CYS	80	0	N4V2CA096F
TEMP CYCLE, 5' RAMP, 10' DWELL	1142	MAX6138BEXR25/V+T	-65C TO 150C	1000	CYS	80	0	N4V2CA096G
			050 TO 4500	4000	0.70	80	0	
TEMP CYCLE, 5' RAMP, 10' DWELL	1142	MAX6138BEXR25/V+T	-650 10 1500	1000	C15	80	0	114 120 A09011